

Amendments to the Claims:

Please amend the claims as follows:

Claims 1-8 (Canceled).

Claim 9 (New): A device used to produce or examine semiconductors, comprising:
a ceramic substrate having a conductor layer formed on the surface thereof or inside thereof and a supporting case,
wherein an external terminal is connected to said conductor layer,
said external terminal is pressed on said conductor layer, or
said external terminal is pressed on another conductor layer connected to said conductor layer.

Claim 10 (New): The device used to produce or examine semiconductors according to claim 9, wherein said device comprises an elastic body, and
elasticity of said elastic body is used to connect said terminal and said conductor layer, or to connect said external terminal and said another conductor layer.

Claim 11 (New): The device used to produce or examine semiconductors according to claim 9, wherein said external terminal is connected to said conductor layer, or said external terminal is connected to said another conductor layer through a non-oxidizable metal layer.

Claim 12 (New): The device used to produce or examine semiconductors according to claim 9, wherein on a face of said ceramic substrate, which is the face opposite to a face

for processing the semiconductor, said external terminal is connected to said conductor layer, or said external terminal is connected to said another conductor layer.

Claim 13 (New): The device used to produce or examine semiconductors according to claim 10, wherein said external terminal is connected to said conductor layer, or said external terminal is connected to said another conductor layer through a non-oxidizable metal layer.

Claim 14 (New): The device used to produce or examine semiconductors according to claim 10, wherein on a face of said ceramic substrate, which is the face opposite to a face for processing the semiconductor, said external terminal is connected to said conductor layer, or said external terminal is connected to said another conductor layer.

Claim 15 (New): The device used to produce or examine semiconductors according to claim 11, wherein on a face of said ceramic substrate, which is the face opposite to a face for processing the semiconductor, said external terminal is connected to said conductor layer, or said external terminal is connected to said another conductor layer.

Claim 16 (New): The device used to produce or examine semiconductors according to claim 13, wherein on a face of said ceramic substrate, which is the face opposite to a face for processing the semiconductor, said external terminal is connected to said conductor layer, or said external terminal is connected to said another conductor layer.